

## N-Channel 200 V (D-S) MOSFET

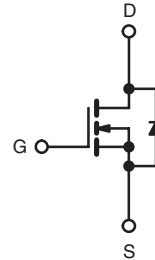
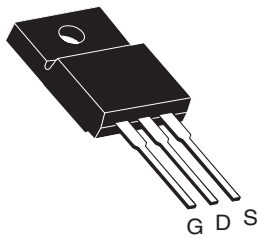
PRODUCT SUMMARY		
V <sub>DS</sub> (V)	200	
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.265
Q <sub>g</sub> (Max.) (nC)	16	
Q <sub>gs</sub> (nC)	5	
Q <sub>gd</sub> (nC)	8	
Configuration	Single	

### FEATURES

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available



TO-220 FULLPAK



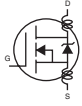

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T <sub>C</sub> = 25 °C, unless otherwise noted					
PARAMETER	SYMBOL		LIMIT	UNIT	
Drain-Source Voltage	V <sub>DS</sub>		200	V	
Gate-Source Voltage	V <sub>GS</sub>		± 20		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	10	A	
		T <sub>C</sub> = 100 °C	6.5		
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>		32		
Linear Derating Factor			0.24	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>		36	mJ	
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>		7.2	A	
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>		3.7	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		P <sub>D</sub>	37	W
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>	
Mounting Torque	6-32 or M3 screw			10	lbf · in
				1.1	N · m

### Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- V<sub>DD</sub> = 25 V, starting T<sub>J</sub> = 25 °C, L = 1.0 mH, R<sub>G</sub> = 25 Ω, I<sub>AS</sub> = 7.2 A (see fig. 12).
- I<sub>SD</sub> ≤ 9.2 A, di/dt ≤ 110 A/μs, V<sub>DD</sub> ≤ V<sub>DS</sub>, T<sub>J</sub> ≤ 175 °C.
- 1.6 mm from case.

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	65	°C/W
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	4.1	

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$ , unless otherwise noted						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	200	-	-	V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25\text{ }^\circ\text{C}, I_D = 1\text{ mA}$	-	0.13	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	2.0	-	4.0	V
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20\text{ V}$	-	-	$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 200\text{ V}, V_{GS} = 0\text{ V}$	-	-	25	$\mu\text{A}$
		$V_{DS} = 160\text{ V}, V_{GS} = 0\text{ V}, T_J = 150\text{ }^\circ\text{C}$	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 4.3\text{ A}^b$	-	0.265	-	$\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 50\text{ V}, I_D = 4.3\text{ A}^b$	2.3	-	-	S
<b>Dynamic</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1.0\text{ MHz}, \text{ see fig. 5}$	-	560	-	$\mu\text{F}$
Output Capacitance	$C_{oss}$		-	260	-	
Reverse Transfer Capacitance	$C_{rss}$		-	110	-	
Drain to Sink Capacitance	$C$		$f = 1.0\text{ MHz}$	-	12	
Total Gate Charge	$Q_g$	$V_{GS} = 10\text{ V}, I_D = 9.2\text{ A}, V_{DS} = 80\text{ V}, \text{ see fig. 6 and 13}^b$	-	-	16	nC
Gate-Source Charge	$Q_{gs}$		-	-	4.4	
Gate-Drain Charge	$Q_{gd}$		-	-	7.7	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 100\text{ V}, I_D = 9.2\text{ A}, R_G = 18\text{ }\Omega, R_D = 5.2\text{ }\Omega, \text{ see fig. 10}^b$	-	8.8	-	ns
Rise Time	$t_r$		-	30	-	
Turn-Off Delay Time	$t_{d(off)}$		-	19	-	
Fall Time	$t_f$		-	20	-	
Internal Drain Inductance	$L_D$	Between lead, 6 mm (0.25") from package and center of die contact 	-	4.5	-	nH
Internal Source Inductance	$L_S$		-	7.5	-	
<b>Drain-Source Body Diode Characteristics</b>						
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode 	-	10	-	A
Pulsed Diode Forward Current <sup>a</sup>	$I_{SM}$		-	32	-	
Body Diode Voltage	$V_{SD}$	$T_J = 25\text{ }^\circ\text{C}, I_S = 7.2\text{ A}, V_{GS} = 0\text{ V}^b$	-	-	2.5	V
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25\text{ }^\circ\text{C}, I_F = 9.2\text{ A}, di/dt = 100\text{ A}/\mu\text{s}^b$	-	130	260	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$		-	0.65	1.3	$\mu\text{C}$
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )				

### Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Pulse width  $\leq 300\text{ }\mu\text{s}$ ; duty cycle  $\leq 2\%$ .

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

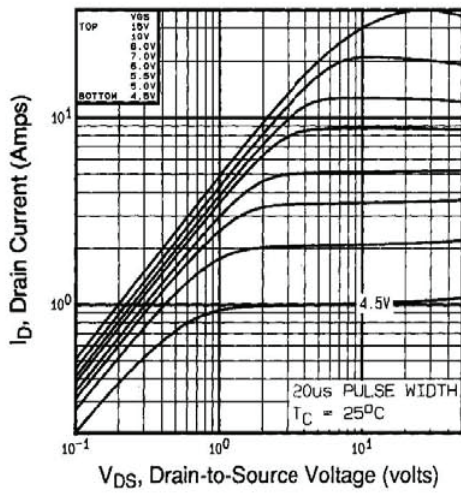


Fig. 1 - Typical Output Characteristics,  $T_C = 25\text{ }^\circ\text{C}$

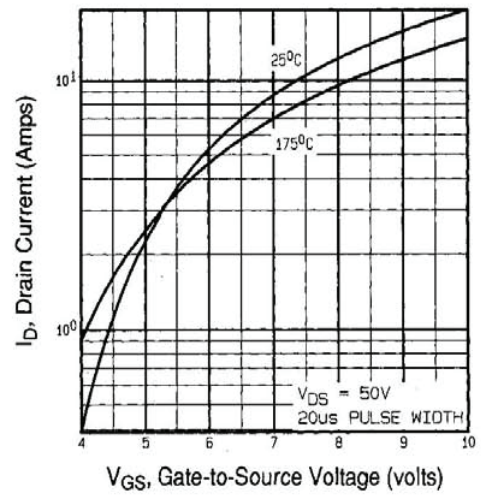


Fig. 3 - Typical Transfer Characteristics

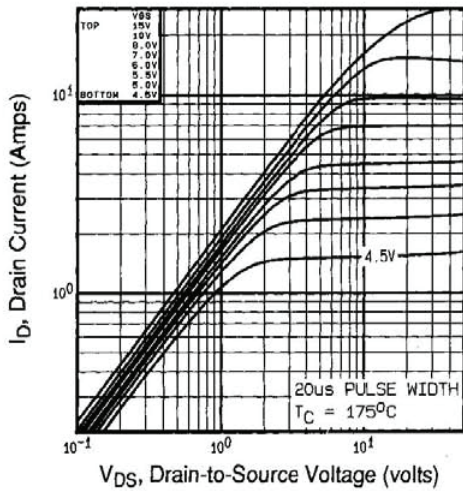


Fig. 2 - Typical Output Characteristics,  $T_C = 175\text{ }^\circ\text{C}$

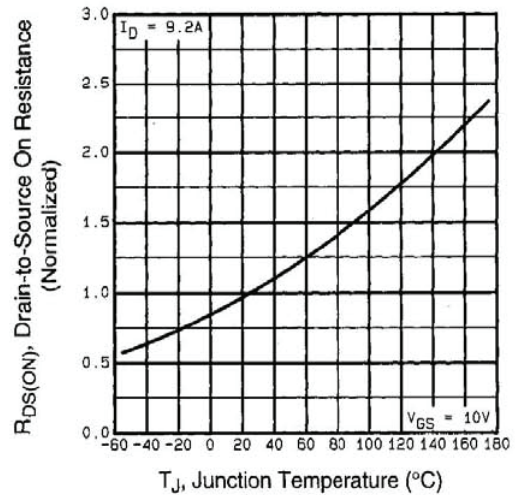


Fig. 4 - Normalized On-Resistance vs. Temperature

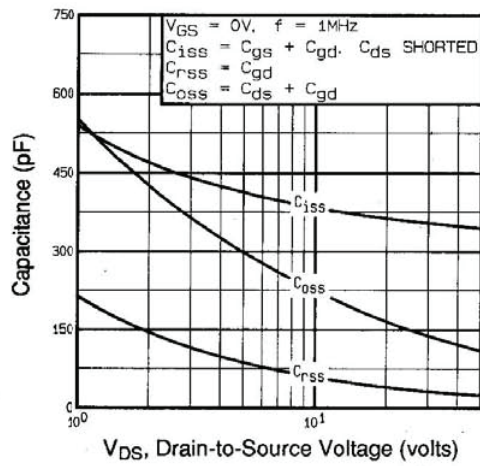


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

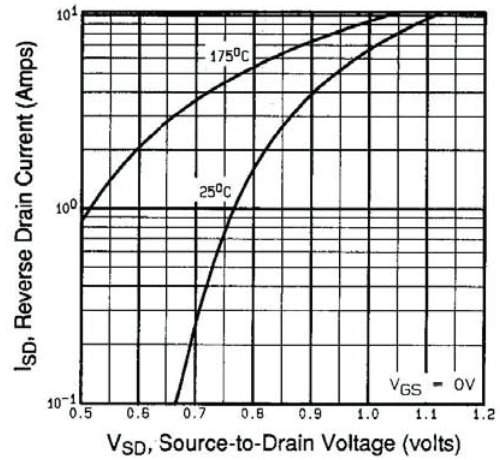


Fig. 7 - Typical Source-Drain Diode Forward Voltage

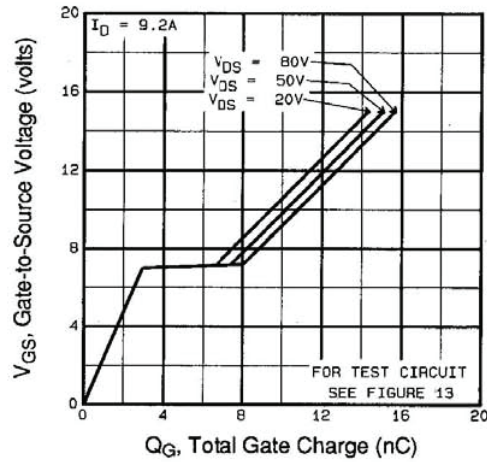


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

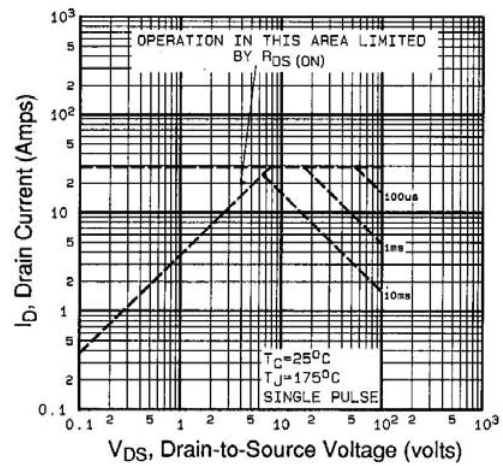


Fig. 8 - Maximum Safe Operating Area

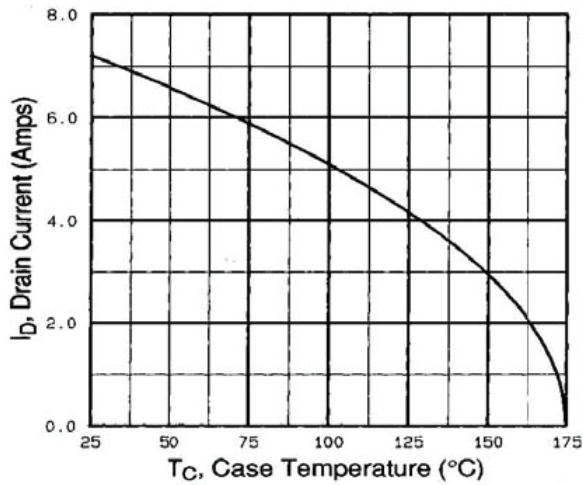


Fig. 9 - Maximum Drain Current vs. Case Temperature

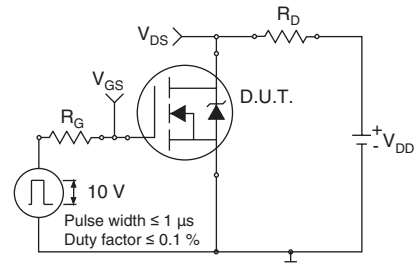


Fig. 10a - Switching Time Test Circuit

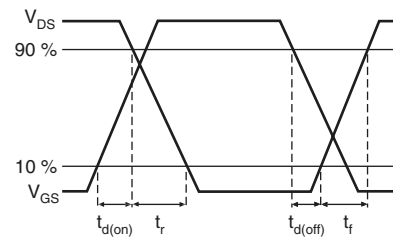


Fig. 10b - Switching Time Waveforms

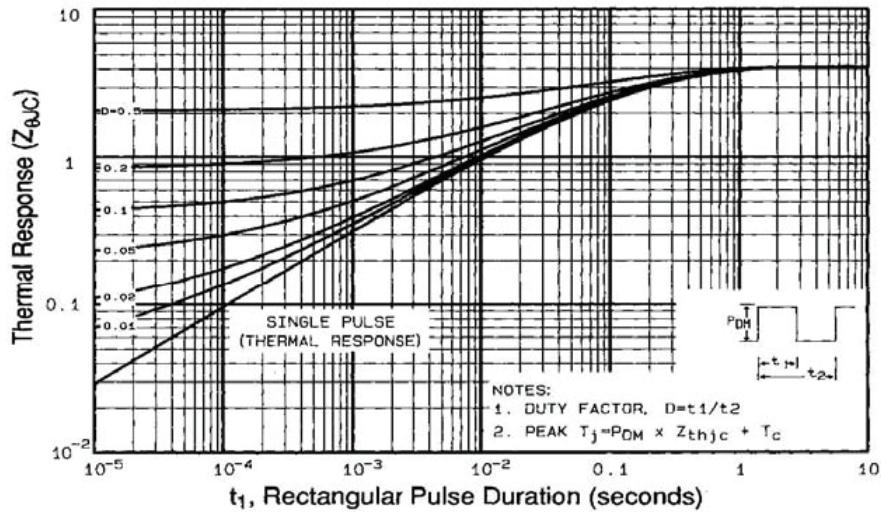


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

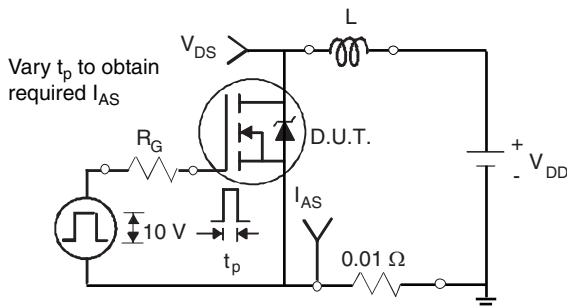


Fig. 12a - Unclamped Inductive Test Circuit

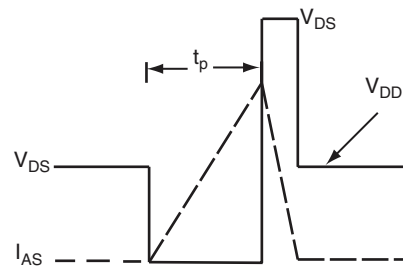


Fig. 12b - Unclamped Inductive Waveforms

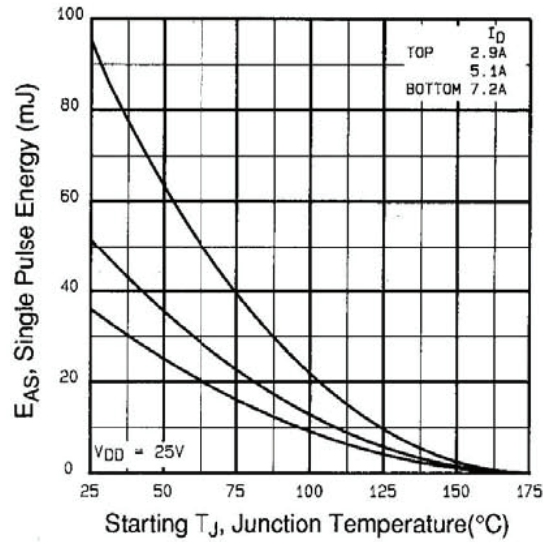


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

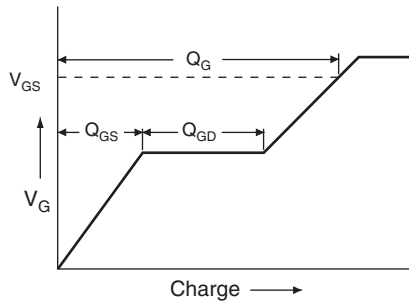


Fig. 13a - Basic Gate Charge Waveform

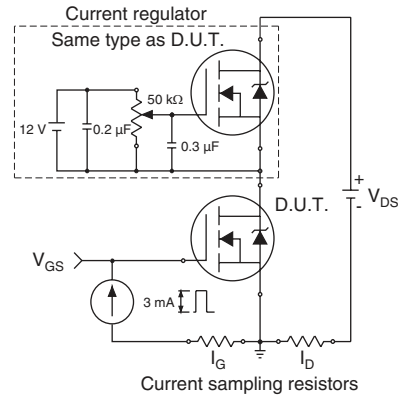


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

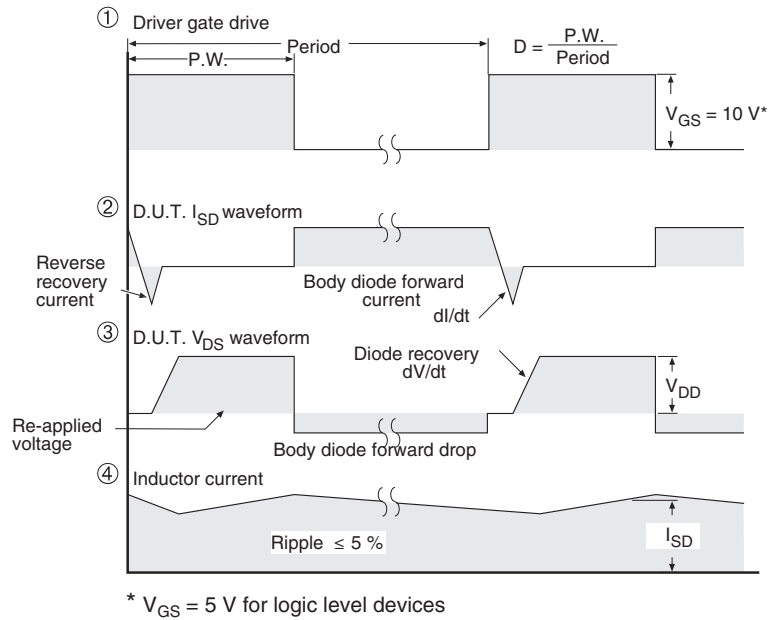
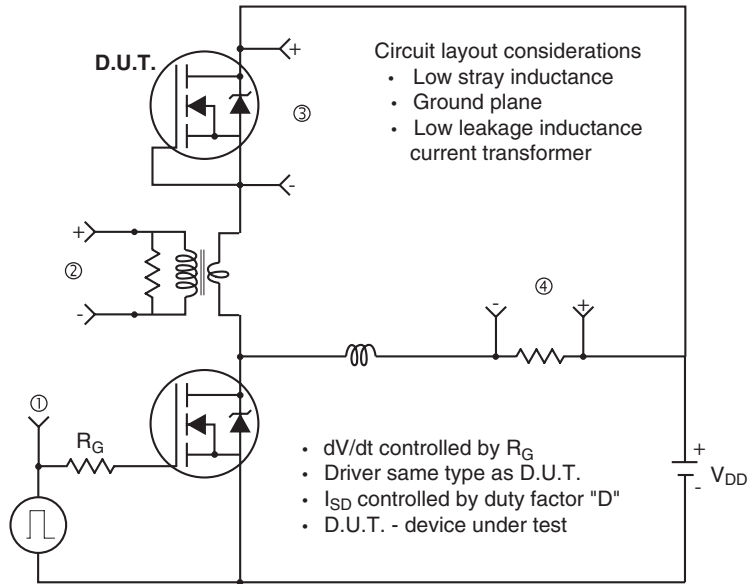


Fig. 14 - For N-Channel

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